

**Octal transceiver with dual enable, non-inverting (3-State)****54ABT623****FEATURES**

- Octal bidirectional bus interface
- 3-State buffers
- Output capability: +48mA/-24mA
- Latch-up protection exceeds 500mA per JEDEC JC40.2 Std 17
- ESD protection exceeds 2000V per MIL-STD 883C Method 3015.6 and 200V per Machine Model

**DESCRIPTION**

The 54ABT623 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 54ABT573 device is an octal transceiver featuring non-inverting 3-State bus compatible outputs in both send and receive directions. The 54ABT623 is designed for asynchronous two-way communication between data busses.

The control function implementation allows for maximum flexibility in timing. This device allows data transmission from the A bus to the B bus or from the B bus to the A bus, depending upon the logic levels at the Enable inputs ( $\overline{OEBA}$  and  $\overline{OEAB}$ ). The Enable inputs can be used to disable the device so that the busses are effectively isolated. The dual-enable configuration gives the 54ABT623 the capability to store data by simultaneously enabling  $\overline{OEBA}$  and  $\overline{OEAB}$ . Each output reinforces its input in this transceiver configuration. Thus when both control inputs are enabled and all other data sources to the two sets of bus lines are at high impedance, both sets of bus lines (16 in all) will remain at their last states.

**ORDERING INFORMATION**

DESCRIPTION	ORDER CODE	PACKAGE DESIGNATOR*
20-Pin Ceramic DIP	54ABT623/BRA	GDIP1-T20
20-Pin Ceramic LLCC	54ABT623/B2A	CQCC2-N20

\* MIL-STD 1835 or Appendix A of 1995 Military Data Handbook

**FUNCTION TABLE**

INPUTS		INPUTS/OUTPUTS	
OEBA	OEAB	An	Bn
L	L	A = B	Inputs
H	H	Inputs	B = A
H	L	Z	Z
L	H	A = B	B = A

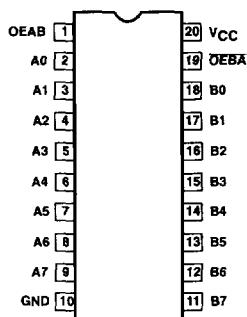
**PIN DESCRIPTION**

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1	OEAB	Output enable input
2, 3, 4, 5 6, 7, 8, 9	A0 - A7	Data inputs/outputs (A side)
18, 17, 16, 15, 14, 13, 12, 11	B0 - B7	Data inputs/outputs (B side)
19	OEBA	Output Enable input
10	GND	Ground (0V)
20	V <sub>CC</sub>	Positive supply voltage

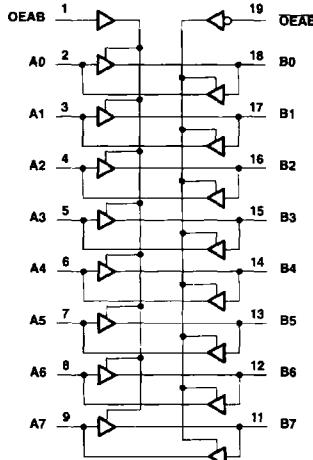
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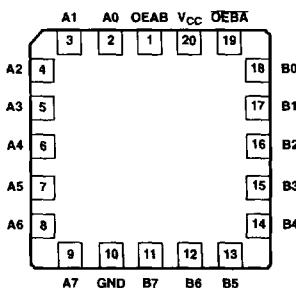
## PIN CONFIGURATION



## LOGIC SYMBOL



## LLCC LEAD CONFIGURATION

ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage range		-0.5 to +7.0	V
I <sub>IK</sub>	DC input diode current	V <sub>I</sub> < 0	-18	mA
V <sub>I</sub>	DC input voltage range <sup>3</sup>		-1.2 to +7.0	V
I <sub>OK</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>O</sub>	DC output voltage range <sup>3</sup>	Output in Off or High state	-0.5 to +5.5	V
I <sub>OUT</sub>	DC output current	Output in Low state	96	mA
T <sub>STG</sub>	Storage temperature range		-65 to +150	°C

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## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		MIN	MAX	
V <sub>CC</sub>	DC supply voltage	4.5	5.5	V
V <sub>I</sub>	Input voltage	0	V <sub>CC</sub>	V
V <sub>IH</sub>	High-level input voltage	2.0		V
V <sub>IL</sub>	Low-level input voltage		0.8	V
I <sub>OH</sub>	High-level output current		-24	mA
I <sub>OL</sub>	Low-level output current		48	mA
Δt/Δv	Input transition rise or fall rate	0	5	ns/V
T <sub>amb</sub>	Operating free-air temperature range	-55	+125	°C

## DC ELECTRICAL CHARACTERISTICS

Unless otherwise stated; V<sub>CC</sub> = MAX, V<sub>I</sub> = V<sub>IL</sub> or V<sub>IH</sub>, t<sub>amb</sub> = -55°C to +125°C.

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS		UNIT	
			T <sub>amb</sub> = -55 to +125 °C			
			MIN	MAX		
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = 4.5V, I <sub>IK</sub> = -18mA		-1.2	V	
V <sub>OH</sub>	High-level output to voltage	V <sub>CC</sub> = 4.5V; I <sub>OH</sub> = -3mA	2.5		V	
		V <sub>CC</sub> = 4.5V; I <sub>OH</sub> = -24mA	2.0		V	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = 4.5V; I <sub>OL</sub> = 48mA		0.55	V	
I <sub>I</sub>	Input leakage current	Control pins	V <sub>I</sub> = GND or V <sub>CC</sub>	±1.0	μA	
		Data pins <sup>6</sup>	V <sub>I</sub> = GND or V <sub>CC</sub>	±100	μA	
I <sub>IH</sub> + I <sub>OZH</sub>	3-State output High current	V <sub>O</sub> = 2.7V, V <sub>I</sub> = V <sub>IL</sub> or 3.0V		50	μA	
I <sub>IL</sub> + I <sub>OZL</sub>	3-State output Low current	V <sub>O</sub> = 0.5V, V <sub>I</sub> = V <sub>IL</sub> or 3.0V		-50	μA	
I <sub>O</sub>	Short-circuit output current <sup>4</sup>	V <sub>O</sub> = 2.5V, V <sub>I</sub> = GND or V <sub>CC</sub>	-50	-180	mA	
I <sub>CCH</sub>	Quiescent supply current	Outputs High, V <sub>I</sub> = GND or V <sub>CC</sub>		250	μA	
I <sub>CCL</sub>		Outputs Low, V <sub>I</sub> = GND or V <sub>CC</sub>		30	mA	
I <sub>CCZ</sub>		Outputs 3-State, V <sub>I</sub> = GND or V <sub>CC</sub>		250	μA	
ΔI <sub>CC</sub>	Additional supply current per input pin <sup>5</sup>	Outputs enabled, one input at 3.4V, other inputs at V <sub>CC</sub> or GND		1.5	mA	
		Outputs 3-State, one input at 3.4V, other inputs at V <sub>CC</sub> or GND		50	μA	
		Outputs 3-State, one enable input at 3.4V, other inputs at V <sub>CC</sub> or GND		1.5	mA	

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## AC ELECTRICAL CHARACTERISTICS

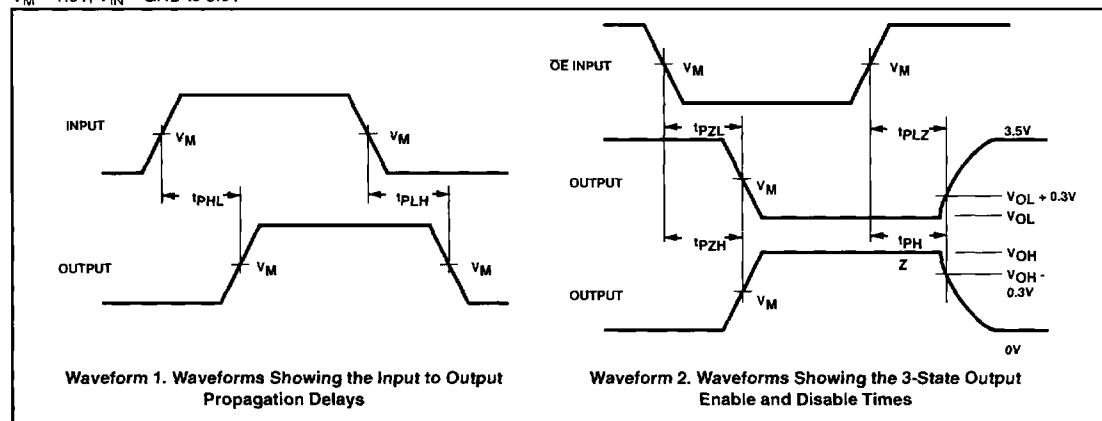
 $V_{DD} = 0V$ ,  $t_R = t_F = 2.5\text{ns}$ ,  $C_L = 50\text{pF}$ ,  $R_L = 500\Omega$ 

SYMBOL	PARAMETER	WAVEFORM	LIMITS					UNIT	
			$T_{amb} \approx +25^\circ\text{C}$ $V_{CC} = +5.0\text{V}$			$T_{amb} = -55^\circ\text{C}$ to $+125^\circ\text{C}$ $V_{CC} = +5.0\text{V} \pm 0.5\%$			
			MIN	TYP	MAX	MIN	MAX		
$t_{PLH}$ $t_{PHL}$	Propagation delay An to Bn or Bn to An	Waveform 1	1.0 1.0	2.8 2.9	4.1 4.2	1.0 1.0	5.0 5.0	ns ns	
$t_{PZH}$ $t_{PZL}$	Output enable time to High and Low level	Waveform 2	1.7 1.7	4.8 4.9	6.5 6.5	1.0 1.0	8.5 8.5	ns ns	
$t_{PHZ}$ $t_{PLZ}$	Output disable time from High and Low level	Waveform 2	1.7 1.7	5.0 5.0	6.5 6.5	1.0 1.0	8.5 8.5	ns ns	

## NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed  $150^\circ\text{C}$ .
3. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
4. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
5. This is the increase in supply current for each input at 3.4V.
6. Input leakage on transceiver data pins also includes  $I_{OZH}$  or  $I_{OZL}$  current from the output circuitry.

## AC WAVEFORMS

 $V_M = 1.5\text{V}$ ,  $V_{IN} = \text{GND}$  to  $3.0\text{V}$ 

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## TEST CIRCUIT AND WAVEFORMS

